CALL FOR PAPERS
The IEEE Latin-American Test Symposium (LATS, previously Latin-American Test Workshop - LATW) is a recognized forum for test and fault tolerance professionals and technologists from all over the world, in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 19th LATS will be invited to re-submit to IEEE Design & Test, Journal of Electronic Testing: Theory and Applications - JETTA (Springer), Journal of Low Power Electronics - JOLPE (American Scientific Publishers), and IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (TCAD).

### Topics of interest include but are not limited to:
- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization
- Hardware Security

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- Defect-Based Test
- Design and Synthesis for Testability
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### Submission Information:

Authors are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium’s webpage: [www.lats.tttc-events.org](http://www.lats.tttc-events.org)

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium’s webpage: [www.lats.tttc-events.org](http://www.lats.tttc-events.org)

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium's webpage. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information, please contact one of the Program Chairs:

- Leticia Bolzani Poehls – PUCRS, Brazil
- Fernanda Lima Kastensmidt - Federal University of Rio Grande do Sul, Brazil
- Fabian Vargas – PUCRS, Brazil
- Vargas@computer.org

### Notification of Acceptance:

Notification of Acceptance: January 13th, 2018

### Camera Ready:

Camera Ready: January 20th, 2018

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- leticia@poehls.com
- Fernanda Lima Kastensmidt - Federal University of Rio Grande do Sul, Brazil
- fglima@inf.ufrgs.br

### Submission Deadline (Title and Abstract):

November 29th, 2017

### Submission (Full paper):

December 9th, 2017

### Notification of Acceptance:

January 13th, 2018

### Camera Ready:

January 20th, 2018

### Location:

Located in the southeast region of Brazil, São Paulo is an alpha global city and is the most populous city in Brazil as well as in the Southern Hemisphere. It exerts strong international influences in commerce, finance, arts and entertainment. With a GDP of US$477 billions, the São Paulo city alone could be ranked 24th globally compared with countries. (2016 Estimates). The metropolis is also home to several of the tallest skyscraper buildings in Brazil, having cultural, economic and political influence both nationally and internationally. It is home to monuments, parks and museums such as the Latin American Memorial, the Ibirapuera Park, Museum of Ipiranga, Sao Paulo Museum of Art, and the Museum of the Portuguese Language. In 2016, lived in the city native inhabitants from 196 different countries. According to a report from 2011, São Paulo was expected to have the third highest economic growth in the world between 2011 and 2025, after London and Mexico City.

### Technical Co-Sponsors:

- The Institute of Electrical and Electronics Engineering, Inc.
- IEEE Council on Electronic Design Automation

### Organized by:

- PUCRS, Brazil
- FEI Centro Universitário FEI

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- IEEE Council on Electronic Design Automation